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## 2D Discharge Characteristics Employing the Calculated Secondary Electron Emission Coefficients as a Function of Xe Partial Pressure

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We carried out 2D discharge simulation to verify the empirically obtained formula based on the ion induced secondary electron emission yields which were measured by a pulsed ion beam method. It was clearly demonstrated that UV generation efficiency, sustain margin and wall voltage etc. showed the different aspects depending on Xe partial pressure and the total gas pressure.